

1 **Revision 1**

2 **Full analysis of feldspar texture and crystal structure by combining X-Ray and Electron**  
3 **techniques**

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## ABSTRACT

21 Feldspar crystals typically show a range of exsolution and polysynthetic twinning textures  
22 which can present problems for their full characterization, but at the same time give important  
23 information about their genesis. We present an integrated procedure for the micro-texture  
24 analysis, twin law identification plus crystal structure refinement of all components in a  
25 feldspar intergrowth. This procedure was applied to perthitic intergrowths in feldspars from  
26 two different pegmatites in the Larvik plutonic complex in the southern part of the Oslo  
27 region, Norway. It revealed that the two starting HT feldspars had similar global chemical  
28 compositions but underwent significantly different cooling histories, with cooling times  
29 probably differing by over an order of magnitude. Powder X-Ray Diffraction with Rietveld  
30 refinement was used for a preliminary identification of the mineral components and  
31 concluding quantitative phase analysis. Electron Microprobe Analysis was used to bracket the  
32 chemical compositions of the constituents. Electron Back-Scatter Diffraction was used to  
33 reveal the texture of the samples, twin laws and spatial distribution and crystallographic  
34 orientation of the crystal domains. Single-grain X-Ray Diffraction recorded by an area  
35 detector was applied for a simultaneous integration of reflection intensities for all  
36 crystallographic domains with different orientations and severe diffraction overlaps. The  
37 crystal structures were refined using the program JANA2006 which allows a simultaneous  
38 calculation for structurally different components. Combined results of various methods helped  
39 improving accuracy and resolving ambiguities which may arise from the application of a  
40 single technique. The approach is widely applicable to the study of mineral intergrowths and  
41 bridges an existing gap in the routinely accessible data on the structural characteristics of rock  
42 constituents.

43 **Keywords:** feldspar, perthite, X-ray diffraction, Electron back-scatter diffraction, mineral  
44 intergrowths, multiphase analysis

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## INTRODUCTION

47           Feldspars are among the most important minerals in the Earth's crust. They show a  
48 broad range of compositional and structural characteristics which present rich information that  
49 can be tied to their genesis, but at the same time complicate their analysis. In particular, due to  
50 extensive solid solutions at temperatures higher than about 700°C and large immiscibility  
51 gaps at lower temperatures, the majority of feldspars begin their history as homogeneous  
52 crystals which subsequently exsolve into immiscible components on cooling. The domain  
53 structure thus formed is further complicated by frequent twinning inside the homogeneous  
54 domains. The two twin laws which are characteristic for this type of transformation twinning  
55 are the albite law with the twin axis normal to (010), and the pericline law with the twin axis  
56 parallel to [010] direction. In both cases sets of very thin polysynthetic lamellae are formed.  
57 These features can present difficulties to the crystal structure analysis by X-ray diffraction and  
58 sometimes to other standard analytical methods like optical microscopy and electron  
59 microprobe. As a consequence of these difficulties, detailed crystal structure determinations  
60 and refinements of various feldspars are not abundant and still do not belong among the  
61 routine methods of analyzing feldspars in rocks even though feldspars are of high importance  
62 in geology. In this work we attempt to overcome the textural obstacles exploiting the  
63 advantages of the area detectors, which have become a standard part of the single-crystal X-  
64 ray diffractometers, combined with several other now broadly available analytical techniques.  
65 The aim was to achieve a routine integrated approach to a full analysis of the crystal structure,  
66 composition and microtexture of feldspars or any other kind of mineral intergrowths.

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## ORIGIN AND DESCRIPTION OF SAMPLES

69           The samples analyzed in this study are two perthitic intergrowths of alkali feldspars originating  
70 from the Larvik plutonic complex which forms the southernmost part of the Oslo region,

71 Norway. The complex is made up of monzonitic rocks, mainly larvikite and its closely related  
72 varieties (Neumann 1980). It consists of 10 semicircular plutons arranged in a manner which  
73 suggests a sequential shift of centres of igneous activity towards the west with a progressive  
74 higher degree of silica under-saturation (Petersen 1978). The age determinations indicate that  
75 the complex was emplaced between 299 and 292 Ma before present (Dahlgren et al. 1996).  
76 The igneous rocks are cut by a number of pegmatites, many of them well exposed due to  
77 intense quarrying activities around Larvik. Quartz-bearing pegmatites dominate in the east  
78 and nepheline-syenite pegmatites in the west (Neumann and Ramberg 1978). The samples  
79 investigated in this work are from the latter type pegmatites.

80 Sample 16 was collected by the first author on the north side of the main road 302  
81 between Stavern and Helgeroa, 400 m west from Jahren Gård and Feriesenter near Gumserød  
82 and about 20-30 m east from the macadam road to Gumserød Gaard. The pegmatite, which  
83 here is exposed on the ground, houses large grey feldspars, several tens of cm in diameter and  
84 full of inclusions of alkaline amphibole, aegirine and ilmenite. Sample 45 was collected by  
85 Søren Bernhard Nielsen from a pegmatite embedded in larvikite in Saga quarry and kindly  
86 provided for this study. The quarry is situated on the SW side of Strandåsen at Mørje, close to  
87 Telemark-Vestfold county border. The feldspars in the pegmatite are represented by dm-sized  
88 red crystals.

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## 90 **EXPERIMENTAL PROCEDURES**

91 Figure 1 represents a schematic diagram depicting the combination of various  
92 techniques and their integration in form of a flow chart identifying different steps during the  
93 iterative refinement procedure. In the following we present the experimental procedures and  
94 details for each of the techniques used at the different steps outlined.

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96 **Powder X-Ray Diffraction (PXRD)**

97 The samples were measured at the X-ray Diffraction Laboratory of the Natural History  
98 Museum, University of Copenhagen. Carefully separated, uniformly coloured fragments of  
99 the large crystals were grinded in an agate mortar to a fine powder which felt completely  
100 smooth under the piston, mounted in sample holders with silicon single-crystal zero-  
101 background plates with cavities of 0.5 mm depth and measured on the diffractometer in  
102 Bragg-Brentano reflecting configuration. The experimental details of the method applied in  
103 this work are presented in Table 1.

104 The program TOPASv4.0 (Bruker-AXS product) was used for Rietveld analysis  
105 (Rietveld 1969) of the data. For the definition of powder-diffraction profiles we used the  
106 fundamental-parameters approach (Cheary and Coelho 1992). Due to the preparation of  
107 samples and the excellent cleavage of feldspars the allowance for preferred orientaiton was  
108 made by refining the March-Dolasse parameters (Dolasse 1986; Table 2). The background  
109 was modelled by Chebyshev polynomials up to the 6<sup>th</sup> order. The emission spectrum of the X-  
110 ray tube used in the refinement was refined on the diagram of the standard sample of CeO<sub>2</sub>  
111 measured under the same conditions as the investigated samples. The results of the Rietveld  
112 refinement are presented in Table 2.

113

114 **Electron Microprobe Analysis (EMPA)**

115 The samples were measured in the Microprobe Laboratory of the Department of  
116 Geography and Geology, University of Copenhagen. Measurements were done on crystal  
117 fragments embedded in epoxy, polished and carbon-coated. The experimental details are  
118 presented in Table 1. The results of the analysis are presented in Table 3. In each spot the  
119 weight percentages of the six oxides were determined compared with the following standards:  
120 corundum (for Al<sub>2</sub>O<sub>3</sub>), hematite (for Fe<sub>2</sub>O<sub>3</sub>), K-feldspar (for K<sub>2</sub>O), albite (for Na<sub>2</sub>O) and

121 wollastonite (for SiO<sub>2</sub> and CaO). Corrections of the raw data were performed using the ZAF  
122 procedure.

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#### 124 **Electron Back-Scatter Diffraction (EBSD) and simultaneous EDS analysis**

125 Crystallographic data were collected using the SEM based EBSD technique (Adams et  
126 al. 1993; Prior et al. 1999). Analyses were performed on uncoated thin-sections at the  
127 Electron Diffraction Laboratory of the Department of Geology and Geochemistry, Stockholm  
128 University. The data were interpreted using Channel 5 analysis suite from HKL Technology  
129 (Oxford instruments). Thin-sections were chemically polished using colloidal silica before  
130 analyses. The automated data collections were made in a rectangular grid using a beam scan.  
131 Further experimental details can be found in Table 1.

132 During acquisition all individual electron backscatter diffraction patterns (EBSPs) were  
133 saved and later analysed in different ways. Reflectors identified by image analysis using the  
134 Hough transform procedure (Duda and Hart 1972) were compared to the theoretically 70  
135 strongest reflectors according to different so-called match units. Match units are theoretical  
136 models that are defined by the crystal lattice and structure parameters. In Step I we used  
137 several standard match units based on literature data (Table 4) as would be the procedure  
138 without previous information about the nature of the analyzed feldspars. In the third Step of  
139 our investigation, we implemented the refined crystal lattice parameters and atomic  
140 parameters derived from the X-ray diffraction measurements. Due to the software restrictions  
141 where for triclinic case only a primitive Bravais lattice is accepted, it was necessary to  
142 transform the data from the standard feldspar orientation (space group C-1) into the P-1 space  
143 group accepted by the HKL Channel 5 (see further explanation in the SXRD section). The  
144 obtained pole figures have been subsequently interpreted in terms of the standard feldspar  
145 orientation and are represented as such in this paper.

146 For both Step I and III we used a so-called “Advanced fit” procedure to improve the  
147 automatic indexing of the full crystallographic orientation. We used a setting where the  
148 system iterates 3 times to find a progressively better solution. We only allowed data which  
149 showed a very good match between the theoretical and calculated reflector positions (MAD –  
150 maximum angular deviation of 0.8). The false data i.e., systematic misindexing was removed  
151 from the dataset, no other processing was performed.

152 In order to double-check the correctness of the phase identification using the EBSPs  
153 we performed simultaneous chemical analysis using the Oxford Instruments INCA system.  
154 Counts for K, Na, Ca and Si  $\alpha$  lines were recorded at each analysis point.

155 In the following, we represent data in several different ways. *Band contrast images*  
156 show a combination of surface topography and crystallographic orientation. They are the map  
157 of the quality of data dependent on the matching to the theoretically expected values with the  
158 best match giving the brightest shade. *EDS maps* give the counts for Na  $K\alpha$ , respectively K  
159  $K\alpha$  lines. *Phase distribution maps* are complementary to the previous, with the phase  
160 information now obtained from the matching of the Kikuchi bands to either Na- or K-feldspar.  
161 *Crystallographic orientation maps* depict different crystallographic orientation in different  
162 colours. *Textural component maps* show the difference in misorientation of each point  
163 analysis relative to a chosen reference orientation (marked with a cross). The crystallographic  
164 information is further presented in pole figures in the (XYZ) reference frame, where Z is out  
165 of plane, using equal area, upper- and lower-hemisphere projections.

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### 167 **Single Grain X-ray Diffraction (SXR)**

168 The measurements were made in the X-ray Diffraction Laboratory of the Natural  
169 History Museum, University of Copenhagen. Like for other methods, the experimental details  
170 can be found in Table 1. For the sample 16 a nearly equidimensional crystal fragment with

171 approximate dimensions 400x500x600  $\mu\text{m}$ , light grey-green in colour, was selected from  
172 among the crushed material. From sample 45 a cylindrical fragment with the height of 100  
173  $\mu\text{m}$  and diameter of 250  $\mu\text{m}$ , light red in colour, was drilled by a diamond-tip drill mounted on  
174 the petrographic microscope (microscope attachment made by Olaf Medenbach, Ruhr-  
175 University Bochum).

176 The data collection was performed using the program SMART (Bruker-AXS  
177 software) with a routine which covers a full reciprocal sphere (Table 5). An automatic search  
178 for Bragg reflections was done by the same program. In both samples the analysis revealed  
179 multiple crystals. The individual parameters and orientations of reciprocal lattices in the  
180 diffraction picture were revealed through an iterative procedure in the program GEMINI  
181 (Bruker-AXS software) from about 1000 reflections with largest  $I/\sigma_I$  harvested from the  
182 recorded data. As the program is originally made for the elucidation of a simpler case of two-  
183 component non-merohedral twins, it was necessary to rerun it several times to determine all of  
184 the components present in the sample. After the two first were determined, their reflections  
185 were removed from the list and the search continued on the rest. Ultimately, the completeness  
186 was checked by optical inspection of a number of recorded detector frames. The overlay  
187 feature of the program SMART was used, where the expected positions of reflections defined  
188 from the orientation matrix are marked on the recorded detector frames.

189 The procedure was greatly helped by the previous knowledge of the unit cell  
190 parameters of the constituent components (PXRD) and the supposed twinning law and the  
191 mutual orientation of the various components (EBSD). It must be noted that the search  
192 program finds always a primitive unit cell. It is obviously important both for the EBSD search  
193 routine (see above in the EBSD section) and for the SXRD reciprocal lattice search to work  
194 with the primitive setting of the feldspar crystal lattice and not with the usual C (or I) setting.



195 Therefore, we report in Table 5 also the crystal lattice parameters for the P lattice setting. The  
196 transformation of the C unit cell of feldspars to the P one is according to the matrix:

$$197 \quad \begin{matrix} 1/2 & -1/2 & 0 \\ 1/2 & 1/2 & 0 \\ 0 & 0 & 1 \end{matrix}$$

$$198 \quad \begin{matrix} 1/2 & -1/2 & 0 \\ 1/2 & 1/2 & 0 \\ 0 & 0 & 1 \end{matrix}$$

$$199 \quad \begin{matrix} 0 & 0 & 1 \\ 1 & 1 & 0 \\ -1 & 1 & 0 \\ 0 & 0 & 1 \end{matrix}$$

200 and the opposite one (from P to C) is:

$$201 \quad \begin{matrix} 1 & 1 & 0 \\ -1 & 1 & 0 \\ 0 & 0 & 1 \end{matrix}$$

$$202 \quad \begin{matrix} 1 & 1 & 0 \\ -1 & 1 & 0 \\ 0 & 0 & 1 \end{matrix}$$

$$203 \quad \begin{matrix} 0 & 0 & 1 \\ 1 & 1 & 0 \\ -1 & 1 & 0 \\ 0 & 0 & 1 \end{matrix}$$

204

205 For a satisfactory refinement of the crystal structure, it is essential to obtain the Bragg-  
206 reflection intensities through a combined integration where all of the different orientational  
207 components in the intergrowth are treated simultaneously with a registration of reflection  
208 overlaps. This is possible in the program SAINT+ (Bruker-AXS product) by specifying  
209 multiple orientation matrices in the orientation file. After the integration, the unit cell  
210 parameters of all the components were refined from the non-overlapped reflections with  $I/\sigma_I >$   
211 10 and the relation matrices between the components were calculated using the same program  
212 (deposited material).

213 The raw reflection file produced through integration and data reduction procedure in  
214 the SAINT+ program was treated subsequently by the TWINABS subroutine of the same  
215 program in order to make an empirical absorption correction and produce the reflection file in  
216 the HKL5 format. Thereafter, the reflection files were read in the program JANA2006  
217 (Petříček et al. 2006) and a multiple phase refinement was done starting from the structure  
218 data for K-feldspar taken from Blasi et al. (1987) and those for the albite from Armbruster et  
219 al. (1990). Atomic coordinates and anisotropic displacement parameters for all atoms were

220 refined together with the amounts of K and Na at the A site constrained to a full occupancy.  
221 The resulting atomic parameters are presented as crystallographic cif-files in Online  
222 Resources 1 to 4.

223 Taking in account the large number of overlaps (Table 5), a combined simultaneous  
224 refinement of crystal structures of all components in the intergrowth is preferable, rather than  
225 using only the non-overlapped reflections and refining each of the components alone. An  
226 exclusion of overlapped reflections would leave out a substantial number from the list, and,  
227 what is of even greater danger, systematically exclude parts of the reciprocal space.

228 For the purpose of the combined refinement, it is most convenient to use a combined  
229 file with reflections of all components with appropriately marked overlaps. For this purpose  
230 the reflection file with HKL5 format as used in SHELX programs (Sheldrick 2008) is very  
231 convenient. On the other hand, the SHELXL program itself can not be used for a  
232 simultaneous refinement of data from different crystal structures (it only can treat twin  
233 intergrowths) but the program JANA2006 is suited for the multiple-phase refinements and  
234 accepts the HKL5 format. The program accepts specification of multiple “twin” matrices and  
235 attribution of each of them to a chosen phase for which separate and specific structure  
236 parameters can be entered.

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## RESULTS

243 **Step I: PXRD, EMPA and EBSD**

244 In both of the investigated samples PXRD suggested a mixture of K- and Na-feldspar.  
245 In the case of K-feldspar components, the refinement of the crystal lattice parameters  
246 suggested in the sample 16 a presence of the high-temperature form (a seemingly monoclinic  
247 lattice) and in the sample 45 the presence of the low-temperature microcline form. For the Na-  
248 feldspar component, a practically pure low temperature albite resulted from the analysis of the  
249 lattice parameters in both samples. For the preliminary Rietveld analysis of the patterns we  
250 used the crystal structure data of Blasi et al. (1987) for the K-feldspar components and the  
251 data of Armbruster et al. (1990) for the Na-feldspar component. We refined only the unit cell  
252 parameters, scale factors, crystallite sizes and the preferred orientation as the structure-  
253 specific parameters. An attempt in refining the atomic coordinates resulted in unreasonable  
254 values of interatomic distances as could be expected for a mixture of different feldspars with  
255 many atomic parameters. The results of the constrained refinements are presented in Table 2.

256 The back-scattered electron images obtained by EMPA instrument gave an indication  
257 of the sizes of the single-phase exsolution domains. As can be seen from Figure 2, the  
258 diameters of the chemically homogeneous lamellae on the polished surface were <10  $\mu\text{m}$  in  
259 thickness in sample 16, whereas they had a much larger thickness, reaching locally to 100  $\mu\text{m}$ ,  
260 in sample 45. Due to the relatively small beam size of about 5  $\mu\text{m}$  it was possible to obtain  
261 relatively reliable chemical analyses of all components in the samples in both cases, although  
262 for sample 16 with more difficulty (Table 3). The chemical analysis gave the following  
263 average compositions of Na- and K-feldspar components in the two samples:  
264  $\text{K}_{0.01(1)}\text{Na}_{1.01(1)}\text{Ca}_{0.01(0)}\text{Al}_{1.00(1)}\text{Si}_{2.98(1)}\text{O}_8$  and  $\text{K}_{0.86(5)}\text{Na}_{0.17(5)}\text{Al}_{1.00(2)}\text{Si}_{2.99(2)}\text{O}_8$  (sample 16) and  
265  $\text{K}_{0.01(0)}\text{Na}_{1.02(2)}\text{Fe}_{0.01(0)}\text{Al}_{0.99(1)}\text{Si}_{2.99(1)}\text{O}_8$  and  $\text{K}_{1.00(1)}\text{Na}_{0.04(1)}\text{Al}_{0.99(1)}\text{Si}_{3.00(1)}\text{O}_8$  (sample 45). They  
266 are in a very good agreement with the compositions obtained later from the crystal structure  
267 refinement (see Step II).

268 For the quantitative orientation data we allowed only very good match between  
269 theoretical and measured reflectors in EBSD. The initial indexing rate for Step I was 42.5 %  
270 and 44.6% for samples 16 and 45, respectively. It should be noted that surface quality related  
271 problems in parts of the analysed areas precluded indexing in ca. 20% and 5% of the total area  
272 of samples 16 and 45, respectively (c.f., Figs. 3 and 4). The used theoretical match units are  
273 given in Table 4. Band contrast, phase distribution and crystallographic orientation obtained  
274 by EBSD combined with simultaneous EDS analysis (Figs. 3 and 4) provided a good idea of  
275 what types of feldspars and twin laws could be expected in the two samples and are in  
276 accordance with the results of PXRD and EMPA.

277 For the albite component in the sample 16 the pole figures showed some highly  
278 deviating individual measurements interpreted as false data. However, the majority of  
279 determinations group in relatively clear unique orientation of the c axis and the two  
280 alternative orientations of both a and the b axes (Fig. 5). For the a axis the two directions are  
281 observed conforming to the Carlsbad twin law, one of them dominant and the other clearly  
282 underrepresented. However, this feature turned out to be a false one during the Step II  
283 analysis (see discussion). For the b-axis direction a splitting characteristic for the albite twin  
284 can be seen in the pole figure. This feature could clearly not be an artefact and was  
285 confirming the presence of this twin law. For the K-feldspar, apart from the false orientations,  
286 the majority of the orientations conform to the orientations of the albite components, however  
287 without the splitting of the b-axis (Fig. 5). The latter is not to be expected to be observable,  
288 anyhow, with the crystal lattice being very close to the monoclinic one. The lamellar structure  
289 as indicated by element mapping as well as the phase distribution in this sample has the  
290 lamination approximately parallel to the crystallographic (010) plane which is also the  
291 composition plane of the albite twin law.

292 For sample 45 both the orientation of the phase lamellae is visible from the phase  
293 distribution and chemistry and their traces are parallel to the (100) plane in this case (Fig. 4).  
294 From the band contrast the albite twin lamellae in the albite component are also visible. A  
295 misorientation suggesting a Carlsbad twin can be registered here as well but also a continuous  
296 spread in orientations of the correctly indexed components (both K-feldspar and albite) (Fig.  
297 6). For albite the presence of the albite twinning was obvious both in the pole figures and  
298 crystallographic orientation maps, but for K-feldspar no definite conclusion was possible in  
299 this stage.

300 The EBSD results in this Step confirmed thus the presence of the two feldspar phases  
301 in both samples and their K-feldspar and Na-feldspar nature and documented the presence of  
302 the albite twin lamellae in the albite components plus questionable Carlsbad twins for all  
303 components. Very fine lamellar structure of sample 16 documented that no single-phase grain  
304 can be separated from this sample, whereas for the sample 45 single phase grains would be in  
305 any case under 100  $\mu\text{m}$  in diameter. All this information was of a great help in the succeeding  
306 SXR analysis (see below).

307

## 308 **Step II: SXR**

309 Three components with different orientations were found by SXR in the sample 16:  
310 one representing K-feldspar and two an albite twin of Na-feldspar. In the case of the sample  
311 45 there were in all four components, because both K-feldspar and Na-feldspar exhibited  
312 albite twins. No indication of the simultaneous pericline twinning, as usual in many  
313 microclines, could be observed. The microscopic inspection of the thin section of the sample  
314 45 also indicated just two twin orientations in both Na- and K-feldspar (Figure 7). Many of  
315 the observed reflections were partly or fully overlapping between the components (Table 5).  
316 This is a consequence of the albite twin law plus the near correspondence in orientations

317 between the K-feldspar and Na-feldspar components. The orientational relations can be  
318 explained by an exsolution from a common single crystal. For example, in the sample 16 the  
319 unique K-feldspar component is symmetrically placed between the orientations of the two Na-  
320 feldspar albite twins, as observed already from the EBSD results (Fig. 5). The relational  
321 matrices between the components and the reflection list with the overlap indications can be  
322 found in Online Resources 5 and 6.

323         The lattice parameters and the values of the bond distances and coordination volumes  
324 for tetrahedral coordinations show that the Na-rich component in both samples corresponds to  
325 the low albite with Al completely ordered at the  $T_{10}$  site (Table 6). There are, though,  
326 substantial differences in the ordering grade of the K-rich components between the two  
327 samples (Table 7). The one from the sample 45 is very close to the known maximally ordered  
328 microcline (Blasi et al. 1987). The ordering grade of the K-feldspar from the sample 16  
329 characterizes it as “orthoclase”. We use this term in a rather broad sense here, referring to K-  
330 feldspars with partial ordering. More important is that the crystal structure data enable us to  
331 quantify accurately the ordering of Al and Si over the tetrahedral sites. The obtained results  
332 place K-feldspar from sample 16 on the ordering diagram quite close to the intermediate  
333 position with almost all Al preferentially ordered in the both of the  $T_1$  sites (Fig. 8). It is  
334 further confirmed by the fact that the crystal structure parameters correspond closely to the  
335 sample A1D from a systematic work on K-feldspars with a high range of ordering grades  
336 from the Adamello Massif (Dal Negro et al. 1978; see Table 7). The amount of Al in the  $T_{10}$   
337 site is around 50%, but, in accordance with the observations of Dal Negro et al. (1978), it has  
338 still not reached this value in  $T_{1m}$  site and the structural symmetry is already a triclinic one.  
339 This confirms the slight deviation of the crystal lattice from ideal monoclinic angles as  
340 suggested by the refinement of crystal lattice parameters which can thus be considered  
341 significant. In other words, the K-component has in the ordering process already passed the

342 field of sanidine and entered the intermediate-microcline state. Likewise, our data confirm the  
343 previously observed deviation from an ideal two-step ordering path in K-feldspar (Fig. 8).

344 The compositions of the two K-feldspars obtained through crystal structure refinement  
345 are  $K_{0.86(1)}Na_{0.14(1)}AlSi_3O_8$  and  $K_{0.93(1)}Na_{0.07(1)}AlSi_3O_8$  for the samples 16 and 45, respectively,  
346 which corresponds very good with the EMPA results.

347

### 348 **Step III. Refined EBSD, final Rietveld refinement of PXRD data.**

349 With the knowledge of the crystal lattice and crystal structure parameters from SXRDR,  
350 we performed the orientation analysis using the same EBSPs acquired for the two samples in  
351 Step I. The indexing percentage changed markedly (see Table 4) and the data were much  
352 more reliable, e.g., points that were indexed as K-feldspar were consistently in areas of high K  
353 content (Figs. 3 and 4). Although the introduction of the crystal structure data from SXRDR  
354 improved the indexing and especially for the sample 45 removed several inaccuracies from  
355 the pole figures, some reflectors still remained with an alternate direction of the *a* axis as  
356 mentioned under Step I, corresponding to what can be regarded as the Carlsbad twinning  
357 where the two crystal lattices are related by a 180° rotation around the *c* axis. This is contrary  
358 to the SXRDR results where no twinning of this kind could be observed. EBSD results can be  
359 explained as common misindexing in feldspars. Both the period of the [-1 0 -1] direction and  
360 its angle to the *c* axis correspond closely to those of the [100] direction. The difference in the  
361 periods and angles is only about 2% in the K-feldspar and lower than 1% in albite. SXRDR is  
362 discriminative enough to detect the presence of Carlsbad twins because of its good angular  
363 resolution and the fact that it records the diffraction from all parts of the sample  
364 simultaneously. In the case of EBSD the orientation is judged from Kikuchi bands of  
365 individual reflectors and the mistake is in the range of the accuracy of the method. Our results  
366 confirm this potential ambiguity in the analysis of feldspars and show that for the final

367 confirmation of the presence or absence of Carlsbad twinning a SXRDR analysis might be  
368 needed. In principle, the Carlsbad twinning should be characterized by relatively well defined  
369 domains already in EBSD. It is a penetration twin consisting of just two domains and  
370 although the contact surface can be complex, the crystallographically defined twins should  
371 correspond to spatially well defined areas with distinct boundaries on EBSD orientation  
372 contrast images. In the case of sample 16 and 45 such spatial relationships were not identified.

373 EBSD analysis shows the textural details of the samples (Figs. 3, 4, 6, 9). In sample 16  
374 the lamellae appear to be parallel to the (010) plane. Our results thus suggest conformity of  
375 the exsolution lamellae and the twin lamellae of the albite component.

376 In sample 45 the angular spread of orientations for all components is about  $6^\circ$  (Fig. 9).  
377 In spite of the angular spread, the albite twin components in albite are clearly visible also on  
378 pole figures (Fig. 6), because the orientations of the angular deviation of the twin splitting and  
379 the angular spread are different. Furthermore, the twin components are clearly discernable in  
380 the orientation map. For the K-feldspar the situation is not so clear. The angular spread is  
381 larger than the expected split angle of  $4.7^\circ$  for an albite twin in microcline. Unfortunately, the  
382 orientation of the angular spread also coincides with the direction of twin splitting masking it  
383 on the pole figures of relatively large areas as the one represented on Figure 6. In this way,  
384 although the albite twinning in microcline observed by SXRDR can not be excluded, it can also  
385 not be completely confirmed by EBSD if bulk data are considered. However, by selecting  
386 data from smaller homogeneous areas, a clear splitting of the b axis in the two directions  
387 conforming to the albite twin law became visible (black boxes, Fig. 6). SXRDR results suggest  
388 that one of the twin domains in microcline is much more dominant than the other; in other  
389 words one of the two twin components occupies much larger volume than its counterpart. The  
390 same relationship is also seen in the EBSD data, where one twin orientation occupies a much  
391 smaller area than its twin counterpart (bright blue data points in Fig. 6).



392 Powder diffraction analysis is superior to other analytical methods in the quantitative  
393 determination of the proportions of phases in the intergrowth. As well documented (see e.g.,  
394 Shim et al. 1996; Balic-Zunic et al. 2011) for a reliable quantitative phase analysis the  
395 refinement of the preferred orientation is mandatory in the case of crystals with prominent  
396 cleavage. In this case we used a combination of the March-Dolasse function (Dolasse 1986)  
397 for the two crystallographic planes known to represent the cleavage directions in feldspars. As  
398 could be expected, the (0 0 1), being the more prominent cleavage, showed a clearly  
399 pronounced effect, whereas the (0 1 0) practically had no effect on preferred orientation  
400 (Table 2).

401 Comparison of the results based on the literature data and those based on the atomic  
402 parameters obtained by the SXR D (Table 2) shows small differences for sample 16 and no  
403 significant differences for sample 45. As mentioned in Step I, the Rietveld refinement had to  
404 be constrained to assumed atomic parameters. Our results show that even with such  
405 constrained refinements one can obtain highly accurate unit cell parameters for albite and K-  
406 feldspar mixtures. The use of the accurate atomic parameters obtained through SXR D  
407 improves the results of the quantitative phase analysis in the case of sample 16 where the  
408 ordering grade of K-feldspar does not match the used literature reference data. It is interesting  
409 that we obtain relatively good results in Step I in spite of using the crystal structure  
410 parameters of the low microcline. To test the influence of various structural parameters, we  
411 tried also refinements with the starting parameters corresponding to the sample A1D from Dal  
412 Negro et al. (1978) which matches closely our results from SXR D and the sample P2B which  
413 represents the most disordered K-feldspar from the same work. The resulting proportions of  
414 albite and K-feldspar from these two refinements were 57:43 and 58:42, respectively, to be  
415 compared to the “real” values of 56:44 (Table 2).

416 The data of the quantitative phase analysis combined with the results of the chemical  
417 analysis (EMPA and SXRD) of the separate phases enable us to calculate the average  
418 composition of the starting high-temperature homogeneous feldspar. They are  $\text{Or}_{0.37}\text{Ab}_{0.63}$  and  
419  $\text{Or}_{0.43}\text{Ab}_{0.57}$  for the samples 16 and 45, respectively (neglecting the minor An component in  
420 the sample 16).

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## DISCUSSION AND CONCLUSIONS

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Our analyses show that sample 16 represents a mesoperthite (Smith and Brown 1988) with an exsolution texture consisting of lens-like lamellae with the shortest diameter under 10  $\mu\text{m}$ . Albite dominates volumetrically over K-feldspar and contains two sets of lamellae twinned after the albite law. The K-feldspar lamellae have  $\text{Or}_{86}\text{Ab}_{14}$  composition and an almost monoclinic crystal lattice with the orientation intermediate between the two twin components of albite. The orientation maps suggest that the long phase domain boundaries are parallel to the (010) twin plane. The structure of the albite corresponds to low albite and that of the K-feldspar to the partially ordered intermediate microcline (orthoclase). The structural and textural characteristics suggest that the coarsening of the exsolution lamellae has stopped in this sample in its incipient stage and the time or temperature was not enough for a maximum ordering in the K-feldspar phase.

Sample 45 represents again a mesoperthite with an average composition similar to the sample 16, with an exsolution texture consisting of coarse lamellae with mostly straight and sharp boundaries with the short diameter reaching up to about 100  $\mu\text{m}$ . Again, albite is in a small surplus and contains two sets of lamellae twinned after albite law. The lamellae of K-feldspar have  $\text{Or}_{93}\text{Ab}_{07}$  composition and are also twinned according to the albite law. The structure of the albite corresponds to low albite and that of the K-feldspar to the maximally

440 ordered low microcline. The long phase boundaries in this case are parallel to the (100) plane.  
441 The pericline twin law could not be confirmed either optically or analytically.

442         The two antiperthites formed by exsolution from homogeneous alkali feldspars which  
443 both had a composition very close to 60 mol% Ab and 40 mol% Or. The cooling history  
444 ended differently for the two samples, as well documented by the textural and crystal structure  
445 characteristics. For the sample 45 a relatively slow and longer cooling can be assumed,  
446 whereas the exsolution texture and degree of ordering of K-feldspar in the sample 16 suggests  
447 a significantly shorter cooling history. Using the TTT diagram of Parsons and Brown (1984),  
448 we can conclude that the development in the sample 16 resembles roughly their curve E' with  
449 an estimated cooling time estimated to about 1000 y, whereas the sample 45 matches better  
450 curves F to H with an estimated cooling time of over 10000 y. It should be noted that this  
451 result mostly depends on the accuracy of the estimated time necessary for the beginning of  
452 monoclinic to triclinic transition and time necessary for the full ordering of Al and Si,  
453 respectively, in the K-feldspar, which produces in TTT diagram a difference of at least one  
454 order of magnitude in time.

455         The two samples show not only largely different textures, but also a different spread of  
456 crystallographic orientations. In the sample 45 with longer cooling history and higher degree  
457 of exsolution development and structural ordering, the deformation spread of orientations is  
458 higher, about 6° over the investigated area (Fig. 9), and actually masks the K-feldspar  
459 twinning. This feature is most probably related to the strain relaxation in the coarsely textured  
460 antiperthite caused by the ordering and change of the crystallographic symmetry in K-feldspar  
461 which would be in accordance with its orientation (the deformation spread is parallel to the  
462 split in the orientation of the b-axis in the two K-feldspar twin components).

463 As the purpose of this work is the evaluation of the combined experimental procedure,  
464 we do not venture in further geological interpretation of results for which a more systematic  
465 study on a larger body of samples from Larvik plutonic complex is needed.

466 We have utilized and combined four different experimental techniques in the analysis  
467 of the feldspar intergrowths. Each of them has aspects which can not be satisfactory covered  
468 by any of the others if truly quantitative data should be obtained. Combining the methods  
469 does not only bring a more complete picture of the sample. Also the individual results are  
470 improved through synergetic influence. In the following, we discuss those aspects of the  
471 various applied methods in some detail.

472 Diffraction analysis of the powdered sample (PXRD) reveals the main mineral  
473 constituents and gives their accurate crystal lattice parameters. It is therefore a valuable tool in  
474 the start of the combined analysis. It can also be performed relatively quickly due to easy  
475 preparation of samples and a short acquisition time compared to other methods. Diffraction  
476 analysis together with the other preliminary analyses (EMPA, EBSD) form the important  
477 background for the understanding of the features of SXR and the full refinement of the  
478 crystal structures of all the individual phases.

479 The Rietveld refinement is used for the analysis of all aspects of the PXRD data.  
480 Unlike different other previously used methods, the Rietveld method does not need individual  
481 extraction of diffraction maxima for a refinement of crystal lattice parameters and is in large  
482 part self-correcting through coupling of the various parameters and their functions. Feldspars  
483 are low-symmetry structures with a large number and a high overlap of diffraction maxima. In  
484 the case of a mixture of alkali feldspars, our results show that reliable results for crystal lattice  
485 parameters can be obtained if the Rietveld analysis is based on atomic parameters of ordered  
486 albite and microcline. Rietveld analysis can therefore be applied already at the beginning,  
487 before the accurate atomic parameters are known from SXR. Our results show that

488 relatively accurate crystal lattice parameters and even quantitative proportions can be obtained  
489 by using the crystal structure parameters of a completely ordered microcline even if the real  
490 sample is only partially ordered. The obtained lattice parameters did not allow classification  
491 of the K-feldspar as low sanidine (monoclinic) or partially ordered microcline (triclinic), due  
492 to a very small deviation of  $\alpha$  and  $\gamma$  angles from orthogonality. Inability to refine  
493 unconstrained atomic parameters and the very small differences obtained with constrained  
494 refinements based on K-feldspars with different degrees of order in the case of sample 16,  
495 show the weakness of PXRD in characterizing the degree of order in feldspars. This aspect,  
496 however, can be treated satisfactory with SXRDR.

497       Whereas fully accurate atomic parameters are not needed for the preliminary values of  
498 the crystal lattice parameters which can be used for EBSD and SXRDR, they are needed for a  
499 fully accurate quantitative phase analysis. It can be seen that the preliminary analysis of the  
500 sample 45 gave already accurate mineral proportions, because the crystal structure models  
501 used in Rietveld refinement matched closely those of the minerals present (low albite and low  
502 microcline). In the case of the sample 16, the results of the quantitative phase analysis can  
503 differ by several % if the wrong degree of order is assumed for the K-feldspar. This has to be  
504 taken in account if partially ordered feldspars are present in the mixture.

505       Electron Microprobe Analysis gives important information about the chemical  
506 composition of the sample. In the case of very fine exsolution textures the spatial resolution  
507 may hamper the determination of the accurate composition of individual components. In this  
508 case, the SXRDR refinement can give the chemical composition of the exsolved phases,  
509 especially when bracketed by the preliminary EMPA results.

510       EBSD is superior in determining the textural relationships of the sample. Accurate  
511 crystal lattice and crystal structure parameters obtained by SXRDR can improve the resolution  
512 and resolve some ambiguities in the case of feldspars. One of the main drawbacks of the

513 EBSD analysis is that without care, systematic misindexing may be interpreted as the  
514 existence of twin laws. Careful assessment of the band contrast, chemical composition  
515 variation and degree of match between theoretical and experimental reflector orientations is  
516 needed, together with a critical evaluation of the potential twin laws (e.g., their known  
517 textural characteristics). The two way integration of EBSD and SXRDR provides improved  
518 data for both analysis techniques. Furthermore, continuous advancement in the algorithms of  
519 automatic EBSD pattern analysis will ensure less misindexing.

520 SXRDR is shown to be capable of getting the accurate crystal structure data even from  
521 complex intergrowths with several components differing in orientation, thanks to the modern  
522 instrumental advances and novel computational methods. It can provide the crystallographic  
523 information about the twin laws and the mutual orientation of the various components and the  
524 full structural state (degree of order and its features) of each component. Addressing such a  
525 complex case as a feldspar intergrowth is substantially aided by a previous knowledge  
526 provided by other three methods applied. It largely helps searching the realistic results among  
527 the possible solutions calculated by the programs which seek to resolve the diffraction picture  
528 into crystallographic components. This technique can not provide the textural information  
529 accessible by EBSD or substitute the quantitative phase analysis of PXRD. The bulk chemical  
530 composition of the components can be relatively accurately calculated from the results of the  
531 crystal structure refinement, but of course no trace element composition which has to be  
532 obtained by EMPA.

533 It is difficult to judge in this case which set of the unit cell parameters can be regarded  
534 more accurate, the one obtained from the PXRD or the one obtained from SXRDR. In the case  
535 of PXRD the complicating factor is the low symmetry of the both phases in the mixture and  
536 the large overlap resulting in broad diffraction maxima, especially in the high-angle region of  
537 the pattern. In SXRDR the patterns are again severed by partial overlap of diffraction spots,

538 both between the different phases and between the non-merohedral twin components. This  
539 can result in inaccuracies of the angle determination for the influenced diffraction spots. The  
540 additional severing factors are the use of the shorter wavelength and generally more complex  
541 three-dimensional aspect of the experiment which is more difficult to calibrate accurately.  
542 However, the results of the both methods show a satisfactory agreement (compare Tables 2  
543 and 5) and no substantial difference in crystal chemical interpretations is introduced by  
544 choosing any of them. We choose to use the crystal lattice parameters as obtained from SXRD  
545 and their calculated esd.s for the report of geometric structural parameters and the crystal  
546 chemical comparisons (Tables 6 and 7).

547       Our results show that accurate information about the various structural properties of  
548 feldspar intergrowths and other similar materials can be obtained by the integration of the  
549 here applied methods; from the full details of the crystal structure of each component, to the  
550 twin and topotactic relations and finally a complete chemical content of the system. We  
551 restricted ourselves to still not widely used methods (apart from EMPA) with potentials of  
552 new insights. Therefore no high resolution transmission electron microscopy was attempted  
553 on the present samples, although it could resolve one remaining open question of this study –  
554 the finer (sub-micron) textural details of the sample 16, where our results suggest  
555 unexpectedly that the long phase boundaries are not perpendicular, but probably parallel to  
556 (010) plane, contrary to a number of previous high-resolution electron microscopy  
557 observations on perthites (Parsons and Brown 1984). The latter analyses are already well  
558 established in investigations of feldspar intergrowths, whereas the purpose of this study was  
559 to establish analysis of crystal intergrowths on another still largely missing level where no  
560 routine approaches have been developed so far. The methods applied here and the approach  
561 we developed bridge an important gap on a mesoscopic level between the well established  
562 and largely applied nanoscopic high-resolution electron microscopy observations of the finest

563 details of intergrowths and the macroscopic observations in field studies. Our results show  
564 that the experimental and computational development has reached the state where the  
565 additional properties, from the detailed crystal structure to the details of crystal growth and  
566 deformation, can be accurately and routinely analysed also in the most complex cases of  
567 crystal intergrowths in feldspars or in any other solid material. We believe that the approach  
568 has a very broad application field in geological and materials science investigations.

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#### REFERENCES CITED

585 Adams, B.L., Wright, S.I., and Kunze, K. (1993) Orientation Imaging - the Emergence of a  
586 New Microscopy. Metallurgical Transactions A-Physical Metallurgy and Materials Science,  
587 24, 819-831.



- 588 Armbruster, T., Buerger, H.B., Kunz, M., Gnos, E., Broennimann, S., and Lienert, C. (1990)  
589 Variation of displacement parameters in structure refinements of low albite. American  
590 Mineralogist, 75, 135-140.
- 591 Balic-Zunic, T., Katerinopoulou, A., and Edsberg, A. (2011) Application of powder X-ray  
592 diffraction and the Rietveld method to the analysis of oxidation processes and products in  
593 sulphidic mine tailings. Neues Jahrbuch für Mineralogie - Abhandlungen, 188, 1, 31-47.
- 594 Blasi, A., de Pol Blasi, C., and Zanazzi, P.F. (1987) A re-examination of the Pellotsalo  
595 microcline: Mineralogical implications and genetic considerations. Canadian Mineralogist,  
596 25, 527-537.
- 597 Cheary, R.W. and Coelho, A.A. (1992) A fundamental parameters approach to X-ray line-  
598 profile fitting. Journal of Applied Crystallography, 25, 109-121.
- 599 Dahlgren, S., Corfu, F., and Heaman, L.M. (1996) U–Pb time constraints, and Hf and Pb  
600 source characteristics of the Larvik plutonic complex, Oslo Paleorift. Geodynamic and  
601 geochemical implications for the rift evolution. V.M. Goldschmidt Conference, Journal of  
602 Conference Abstracts, 120, Cambridge Publications.
- 603 Dal Negro, A., de Pieri, R., Quarenzi, S., and Taylor, W.H. (1978) The crystal structures of  
604 nine K feldspars from the Adamello Massif (Northern Italy). Acta Crystallographica B, 34,  
605 2699-2707.
- 606 Dolase, W.A. (1986) Correction of intensities for preferred orientation in powder  
607 diffractometry: Application of the March model. Journal of Applied Crystallography, 19, 267-  
608 272.
- 609 Duda, R.O. and Hart, P.E. (1972) Use of the Hough Transformation to Detect Lines and  
610 Curves in Pictures. Communications of the ACM, 15, 11–15.

- 611 Finney, J.J. (1962) The crystal structure of carminite and authigenic maximum microcline.  
612 Thesis, University of Wisconsin.
- 613 Fleet, S.G., Chandrasekhar, S., and Megaw, H.D. (1966) The structure of bytownite ('body-  
614 centred anorthite'). *Acta Crystallographica*, 21, 782-801.
- 615 Neumann, E.R. and Ramberg, I.B., Editors (1978) *Petrology and geochemistry of continental*  
616 *riffts: Volume I*. D. Reidel Publishing Company, Dordrecht.
- 617 Neumann, E.R. (1980) Petrogenesis of the Oslo Region larvikites and associated rocks.  
618 *Journal of Petrology*, 21, 499-531.
- 619 Parsons, I. and Brown, W.L. (1984) Feldspars and the thermal history of igneous rocks. In  
620 W.L. Brown, Ed, *Feldspars and Feldspathoids*, p. 317-371. D. Reidel Publishing Company,  
621 Dordrecht.
- 622 Petersen, J.S. (1978) Structure of the larvikite-lardalite complex, Oslo-Region, Norway, and  
623 its evolution. *Geologischen Rundschau*.
- 624 Petricek, V., Dusek, M., and Palatinus, L. (2006) JANA2006. Institute of Physics, Czech  
625 Academy of Sciences, Prague, Czech Republic.
- 626 Prince, E., Donnay, G., and Martin, R.F. (1973) Neutron diffraction refinement of an ordered  
627 orthoclase structure. *American Mineralogist*, 58, 500-507
- 628 Prior, D.J., Boyle, A.P., Brenker, F., Cheadle, M.C., Day, A., Lopez, G., Peruzzo, L., Potts,  
629 G.J., Reddy, S., Spiess, R., Timms, N.E., Trimby, P., Wheeler, J., and Zetterström, L. (1999)  
630 The application of electron backscatter diffraction and orientation contrast imaging in the  
631 SEM to textural problems in rocks. *American Mineralogist*, 84, 1741-1759.
- 632 Rietveld, H.M. (1969) A profile refinement method for nuclear and magnetic structures.  
633 *Journal of Applied Crystallography* 2, 65-71.

- 634 Sheldrick, G.M. (2008) A short history of SHELX. *Acta Crystallographica*, A64, 1, 112-122.
- 635 Shim, S.H., Kim, S.J., and Ahn, J.H. (1996) Quantitative analysis of alkali feldspar minerals  
636 using Rietveld refinement of X-ray diffraction data. *American Mineralogist*, 81, 1133-1140.
- 637 Smith, J.V. and Brown, W.L. (1988) *Feldspar minerals*, vol. I. Springer-Verlag, Berlin.
- 638 Winter, J.K., Ghose, S., and Okamura, F.P. (1977) A high temperature study of the thermal  
639 expansion and the anisotropy of the sodium atom in low albite. *American Mineralogist*, 62,  
640 921-933.

641 Table 1. Experimental details of the applied instrumental techniques.

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PXRD

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Instrument	Bruker-AXS D8
Operating power	40kV 40mA
Monochromator	Primary Ge(111)
Wavelength	CuK $\alpha$ 1 (1.54056 Å)
Goniometer radius	21.75 cm
Detector, range	Linear PSD (Lynxeye), 3.3°
Fixed divergence slit	0.2 mm (0.1°)
Receiving slit	8 mm
2theta range	10° – 100°
Step size increment	0.02°
Time per step	4 sec
Temperature	299(1) K

EMPA

Instrument	JEOL JXA-8200
Operating power	15 kV 10 nA
Detectors (quantitative analysis)	WDS
Beam diameter	5 $\mu$ m
Working distance	11 mm
Counting time	10 sec

EBSD

Instrument	Phillips XL-30 FEG-ESEM
Operating power	20 keV (~0.8 nA)
Detector	Nordlys
Working distance	15 mm
Step size	0.3 $\mu$ m (sample 16) 3 $\mu$ m (sample 45)

SXRD

Instrument	Bruker-AXS four-circle diffractometer
Operating power	40 kV 40 mA
Monochromator	flat graphite
Wavelength	MoK $\alpha$ (0.71073 Å)
Detector	area-detector Smart 1000CCD
Collimator	0.5 mm
Data collection range (2theta)	to 50°
Working distance	4 cm
Crystal rotation between exposures	0.2°
Exposure	10 sec
Number of exposures per sample	2800
Temperature	299(1) K

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645 Table 2. Results of Rietveld refinement with (a) starting parameters from the literature  
 646 (Armbruster et al. 1990; Blasi et al. 1987), (b) starting parameters from SXRD data.  
 647

	Sample 16		Sample 45	
	(a)	(b)	(a)	(b)
Rexp	3.27	3.27	3.32	3.33
Rwp	12.92	13.84	12.11	12.22
Rp	9.52	10.15	9.41	9.42
$\chi^2$	3.95	4.24	3.64	3.67
<b>Na-FELDSPAR</b>				
RBragg	4.328	5.471	6.661	7.387
a (Å)	8.132(1)	8.131(1)	8.1430(3)	8.1424(3)
b (Å)	12.801(2)	12.796(2)	12.7897(4)	12.7893(4)
c (Å)	7.160(1)	7.158(1)	7.1612(2)	7.1609(2)
$\alpha$ (°)	94.099(6)	94.131(6)	94.260(2)	94.259(2)
$\beta$ (°)	116.611(4)	116.609(4)	116.607(1)	116.607(1)
$\gamma$ (°)	87.896(6)	87.871(6)	87.680(2)	87.681(2)
Crystallite size (nm)	180(7)	176(8)	1770(550)	1120(180)
Preferred orientation <sup>a</sup>	0.91(1); 0.503(7)	0.966(8); 0.415(7)	0.719(9); 0.573(5)	0.740(8); 0.555(5)
<b>K-FELDSPAR</b>				
Rbragg	5.073	5.825	6.546	6.492
a (Å)	8.582(1)	8.579(1)	8.5820(3)	8.5815(3)
b (Å)	12.967(2)	12.961(2)	12.9666(4)	12.9662(4)
c (Å)	7.194(1)	7.193(1)	7.2234(2)	7.2230(2)
$\alpha$ (°)	90.028(7)	90.046(7)	90.638(2)	90.636(2)
$\beta$ (°)	116.103(4)	116.102(4)	115.958(2)	115.959(2)
$\gamma$ (°)	89.627(6)	89.609(5)	87.700(2)	87.701(2)
Crystallite size (nm)	352(34)	327(32)	516(31)	439(22)
Preferred orientation <sup>a</sup>	0.942(8); 0.467(7)	0.930(8); 0.459(7)	0.782(8); 0.544(6)	0.803(7); 0.516(5)
Ab wt%	54	56	52	52
Or wt%	47	44	48	48

648  
 649 <sup>a</sup> for the (010) and the (001) planes, respectively.

650 Table 3. Results of the chemical analysis (EMPA).  
 651

sample	oxide	K <sub>2</sub> O	Na <sub>2</sub> O	CaO	Fe <sub>2</sub> O <sub>3</sub>	Al <sub>2</sub> O <sub>3</sub>	SiO <sub>2</sub>	Total
16 Na- feldspar <sup>a</sup>	wt%	0.13	11.91	0.29	0.08	19.38	67.87	99.66
	esd	0.17	0.16	0.02	0.05	0.26	0.88	1.15
	range	0.03- 0.51	11.60- 12.08	0.26- 0.32	0.02- 0.17	18.98- 19.71	66.66- 68.95	98.21- 101.18
16 K- feldspar <sup>b</sup>	wt%	14.63	1.96	0.04	0.12	18.38	64.97	100.10
	esd	0.74	0.62	0.05	0.18	0.39	1.38	1.52
	range	13.65- 15.91	0.89- 2.67	0.00- 0.13	0.01- 0.56	17.85- 18.86	63.16- 67.52	98.37- 103.40
45 Na- feldspar <sup>c</sup>	wt%	0.10	12.01	0.01	0.16	19.04	68.20	99.52
	esd	0.02	0.12	0.01	0.09	0.24	1.13	1.21
	range	0.07- 0.14	11.77- 12.15	0-0.03	0.02- 0.26	18.64- 19.50	66.57- 69.98	98.05- 101.18
45 K- feldspar <sup>c</sup>	wt%	16.92	0.43	0	0.06	18.11	65.03	100.56
	esd	0.23	0.08	-	0.05	0.20	0.79	1.03
	range	16.72- 17.41	0.26- 0.49	0	0-0.16	17.60- 18.33	63.93- 66.28	99.31- 102.12

652 <sup>a</sup>Average of 7 points

653 <sup>b</sup>Average of 8 points

654 <sup>c</sup>Average of 10 points

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660 Table 4. EBSD indexing parameters and summary of results  
 661

Sample No.; phase	Step I			Step III		
	Match unit	Indexing%	Twin laws	Match unit	Indexing%	Twin laws
16; K-feldspar	orthoclase (Prince et al. 1973)	18	Carlsbad (false) <sup>a</sup>	orthoclase (SXR – this work)	21.2	None
16; Na-feldspar	low albite (Winter et al. 1977)	31.5	albite Carlsbad (false) <sup>a</sup>	low albite (SXR – this work)	40.8	albite
45; K-feldspar	microcline (Finney 1962)	34.6	Carlsbad (false) <sup>a</sup>	microcline (SXR – this work)	38.0	albite
45; Na-feldspar	bytownite (Fleet et al. 1966)	10.0	albite Carlsbad (false) <sup>a</sup>	low albite (SXR – this work)	31.8	albite

662

663 <sup>a</sup>see text for explanation

664 Table 5. Crystal lattice parameters and crystal structure refinement details.  
 665

	sample 16		sample 45	
<b>ALBITE</b>	C-setting	P-setting	C-setting	P-setting
<i>a</i> (Å)	8.133(2)	7.453	8.140(2)	7.445
<i>b</i> (Å)	12.81(1)	7.718	12.799(4)	7.721
<i>c</i> (Å)	7.171(2)	7.171	7.161(2)	7.161
$\alpha$ (°)	94.10(3)	107.17	94.22(2)	107.27
$\beta$ (°)	116.59(3)	100.53	116.58(1)	100.45
$\gamma$ (°)	87.79(1)	115.19	87.70(1)	115.11
<i>V</i> (Å <sup>3</sup> )	666.9(8)	333.4	665.3(3)	332.7
Range of Miller indices <sup>a</sup>	-11<h<11 -18<k<18 -10<l<10		-9<h<9 -15<k<15 -8<l<8	
Non-overlapped reflections / unique	2754/1767		1705/1025	
<b>K-FELDSPAR</b>	C-setting	P-setting	C-setting	P-setting
<i>a</i> (Å)	8.598(2)	7.749	8.579(2)	7.636
<i>b</i> (Å)	12.970(3)	7.812	12.972(4)	7.913
<i>c</i> (Å)	7.200(1)	7.200	7.227(2)	7.227
$\alpha$ (°)	90.029(7)	104.05	90.57(2)	104.19
$\beta$ (°)	116.137(5)	104.12	115.93(2)	103.72
$\gamma$ (°)	89.498(8)	112.92	87.78(2)	113.06
<i>V</i> (Å <sup>3</sup> )	720.8(3)	360.4	723(2)	361.5
Range of Miller indices <sup>a</sup>	-12<h<8 -18<k<18 -9<l<10		-10<h<10 -15<k<15 -8<l<8	
Non-overlapped reflections / unique	2382/1153		1906/1089	
<b>global refinement details</b>				
reflections total/ <i>I</i> > 3 $\sigma$	7035/6553		5265/3735	
parameters	238		239	
Goodness-of-fit, <i>S</i> <sup>b</sup>	3.26		2.25	
R / wR ( <i>I</i> > 3 $\sigma$ ) <sup>c</sup>	3.46% / 5.05%		4.47% / 5.78%	
R / wR (all data) <sup>c</sup>	3.69% / 5.09%		6.26% / 5.86%	
volume proportions a1:a2:k1:k2 <sup>d</sup>	32:26:42		21:19:46:14	

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667 <sup>a</sup> ranges are as for the C-setting

668 <sup>b</sup>  $S = \{\sum[w(F_o^2 - F_c^2)^2]/(n-p)\}^{1/2}$

669 <sup>c</sup>  $R = \sum | |F_o| - |F_c| | / \sum |F_o|$ ;  $wR = \{\sum[w(F_o^2 - F_c^2)^2]/\sum[w(F_o^2)^2]\}^{1/2}$ ;  $w = 1/\sigma^2$

670 *F*<sub>o</sub>, *F*<sub>c</sub> = observed and calculated structure factors, respectively

671 *n*, *p* = number of observations and number of parameters, respectively

672 <sup>d</sup> a1, a2 are albite twin components, k1, k2 K-feldspar twin components

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675 Table 6. Sizes of the coordination polyhedra of T (Si and Al) and A (Na) atomic sites in the  
 676 crystal structures of Na-feldspars from samples 16, 45 and low albite (Armbruster et al. 1990).  
 677

Site	average bond length (Å)			volume of the coordination polyhedron (Å <sup>3</sup> )		
	16	45	low albite	16	45	low albite
T <sub>1o</sub> (Al)	1.739(7)	1.749(10)	1.742(5)	2.67(3)	2.72(4)	2.69(1)
T <sub>1m</sub> (Si)	1.615(10)	1.615(16)	1.610(12)	2.16(3)	2.16(4)	2.14(1)
T <sub>2o</sub> (Si)	1.616(12)	1.618(16)	1.615(15)	2.16(3)	2.17(4)	2.15(1)
T <sub>2m</sub> (Si)	1.618(22)	1.623(24)	1.616(23)	2.17(3)	2.19(4)	2.16(1)
A <sup>a</sup> (Na)	2.79(38)	2.81(40)	2.79(40)	35.9(2)	36.3(3)	35.74(7)

678 <sup>a</sup>for the coordination number 9

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Table 7. Sizes of the coordination polyhedra of T (Si and Al) and A (K and Na) atomic sites  
 in the crystal structures of K-feldspars from samples 16, 45, A1D K-feldspar (Dal Negro et al.  
 1978), and maximum microcline (Blasi et al. 1987).

Site	average bond length (Å)				volume of the coordination polyhedron (Å <sup>3</sup> )			
	16	A1D	45	microcline	16	A1D	45	microcline
T <sub>1o</sub> (Al+Si)	1.680(5)	1.673(5)	1.740(5)	1.737(7)	2.42(1)	2.40(1)	2.69(2)	2.679(9)
T <sub>1m</sub> (Si+Al)	1.654(9)	1.651(7)	1.622(20)	1.613(18)	2.31(1)	2.30(2)	2.18(2)	2.147(8)
T <sub>2o</sub> (Si)	1.622(8)	1.623(9)	1.611(18)	1.614(18)	2.18(1)	2.19(1)	2.14(2)	2.152(8)
T <sub>2m</sub> (Si)	1.622(9)	1.622(9)	1.616(24)	1.614(24)	2.18(1)	2.18(1)	2.16(2)	2.146(8)
A <sup>a</sup> (K+Na)	2.97(12)	2.97(13)	2.98(17)	2.97(17)	43.1(1)	43.1(1)	43.4(2)	43.2(2)

685 <sup>a</sup>for the coordination number 9

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707 **Figure Captions**

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709 Figure 1. Flow chart illustrating the iterative, step-wise integration of the used analytical  
710 methods employed in this study (see text for details)

711 Figure 2. Backscatter Electron Image (BSE) of the (a) sample 16 and (b) sample 45 analyzed  
712 by EMPA; note the very fine laminations (1-10  $\mu\text{m}$  width) of the two feldspar components  
713 (light versus dark grey) in sample 16, while for sample 45 domains of different feldspar are up  
714 to 100  $\mu\text{m}$  wide

715 Figure 3. Sample 16. EBSD and EDS analysis: (a) band contrast image representing data  
716 quality (X mark surface features preventing EBSD analysis), (b) EDS map for Na  $\alpha$ , (c) EDS  
717 map for K  $\alpha$ , (d) phase distribution map after Step I (e) phase distribution map after Step III

718 Figure 4. Sample 45. EBSD and EDS analysis: (a) band contrast image representing data  
719 quality, (b) EDS map for Na  $\alpha$ , (c) EDS map for K  $\alpha$ , (d) phase distribution map after Step I  
720 (e) phase distribution map after Step III

721 Figure 5. Pole figures for sample 16 obtained by EBSD (upper and lower hemisphere  
722 projections). The two albite component orientations are shown as well as the K-feldspar  
723 orientation; note that the trace of the lamellar structure seen in Figure 5 is subparallel to the  
724 (010) plane.

725 Figure 6. Pole figures and crystallographic orientation map for sample 45; the trace of the  
726 boundary between K-feldspar and albite is parallel to the trace of the (100) plane.

727 Figure 7. Photograph of the thin section from sample 45. Crossed polars. Field of view  
728 (horizontal) is 600  $\mu\text{m}$ .

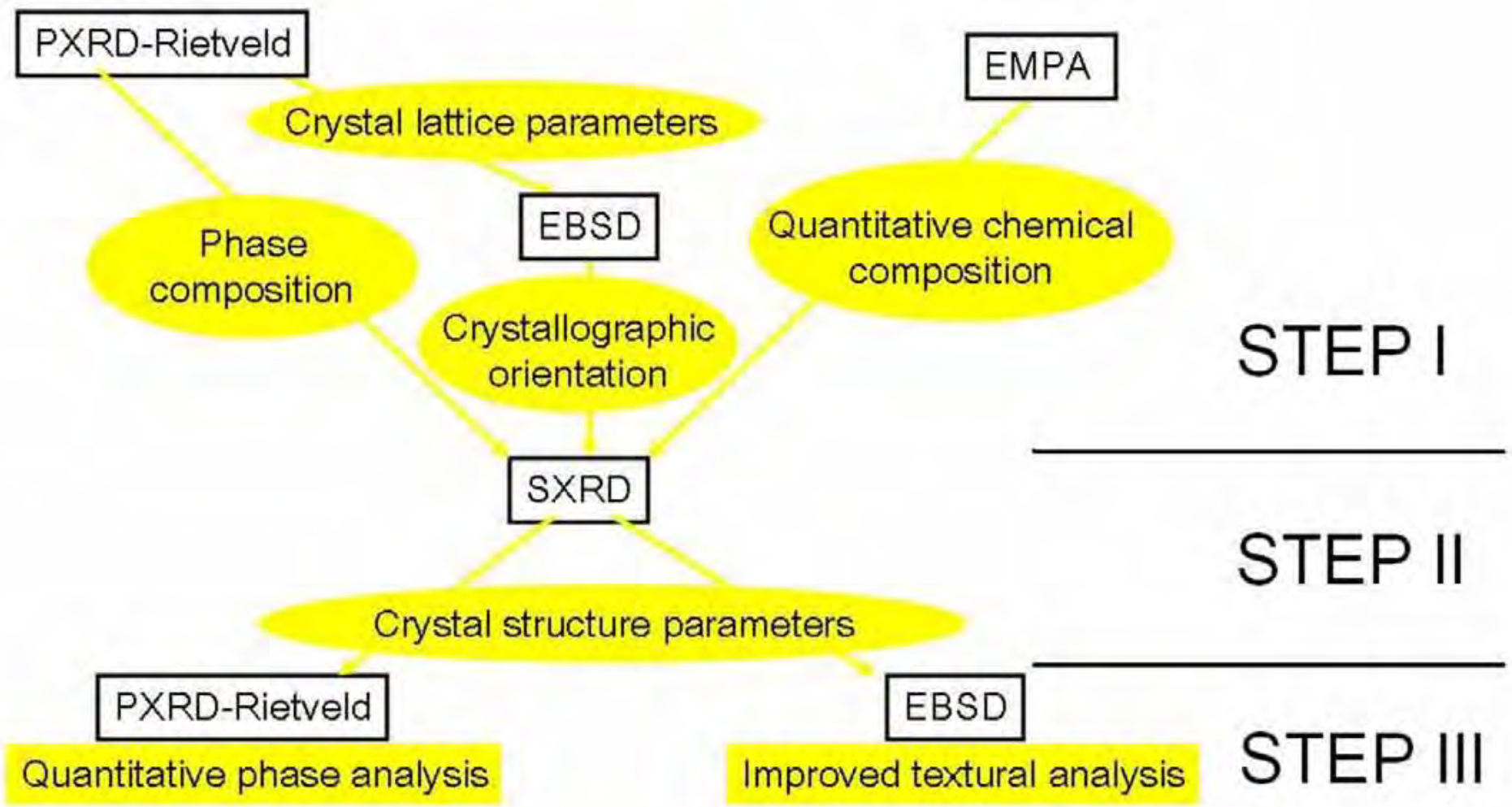
729 Figure 8. Relations of the volumes of coordination polyhedra for the tetrahedral sites in the  
730 two K-feldspars. The horizontal axis represents all sites, the vertical only the largest one.

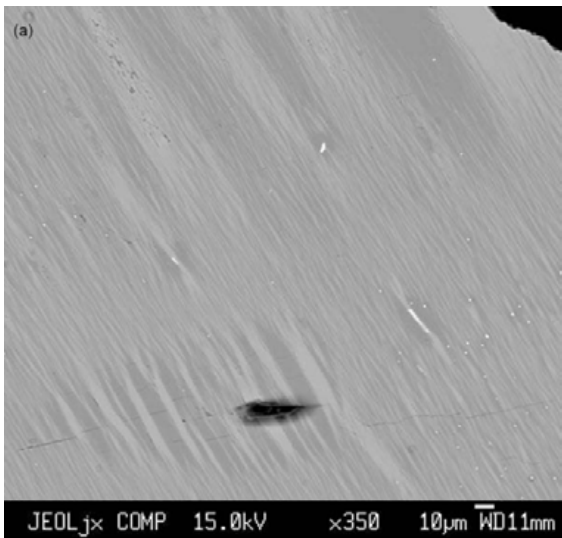
731 Open circles are for sample 16, filled squares for sample 45. The lines represent the expected  
732 trends for the two step (full) or one step (stippled) ordering process.

733 Figure 9. Textural component maps for sample 45 for all feldspar components, showing a  
734 spread of orientation of up to 6° across the whole analysed area

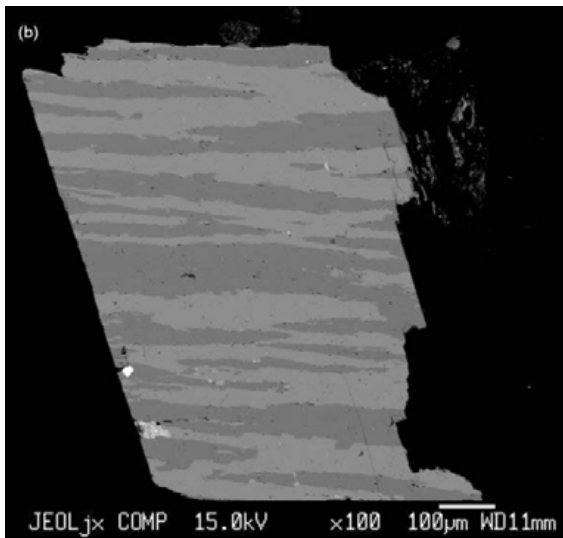
735

- 736 Deposited material, online resource captions
- 737 **OR 1.** Crystal structure information and list of observed and calculated structure factors for  
738 the albite component in sample 16
- 739 **OR 2.** Crystal structure information and list of observed and calculated structure factors for  
740 the K-feldspar component in sample 16
- 741 **OR 3.** Crystal structure information and list of observed and calculated structure factors for  
742 the albite component in sample 45
- 743 **OR 4.** Crystal structure information and list of observed and calculated structure factors for  
744 the K-feldspar component in sample 45
- 745 **OR 5.** Orientation and relation matrices for crystallographic components and the list of  
746 reflections in HKL5 format for the sample 16
- 747 **OR 6.** Orientation and relation matrices for crystallographic components and the list of  
748 reflections in HKL5 format for the sample 45
- 749

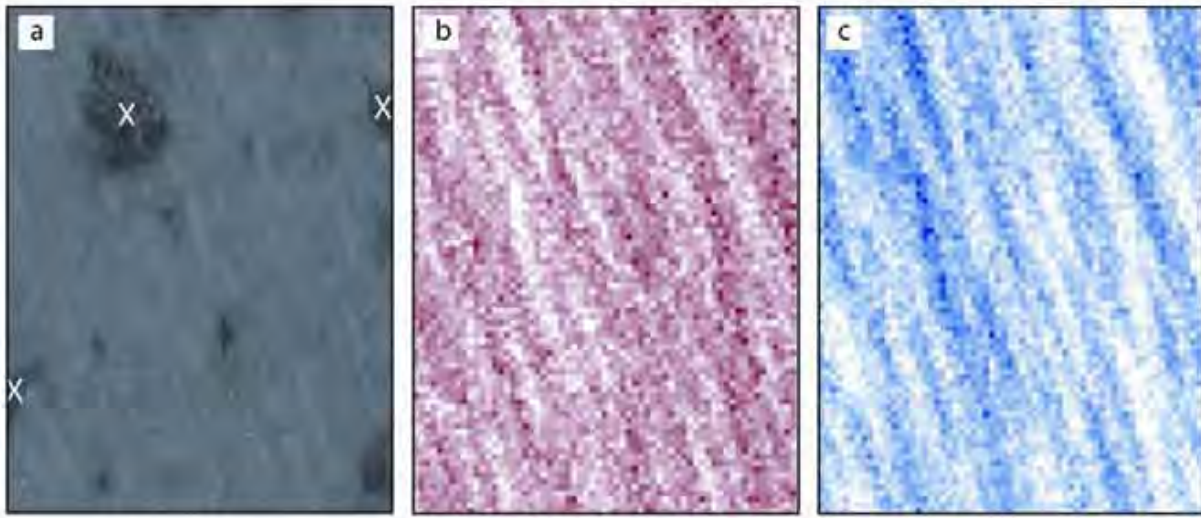






(b)

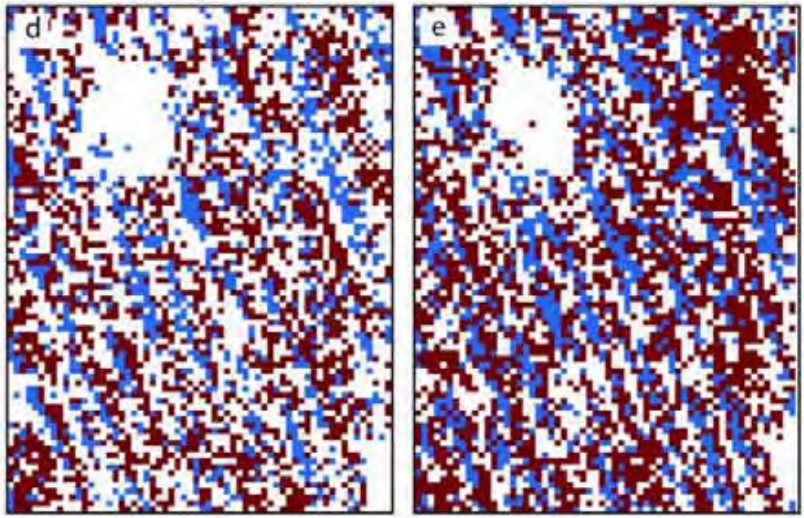


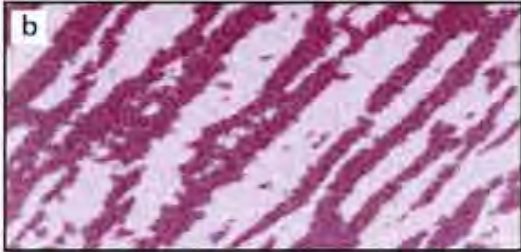
JEOL\_jx COMP 15.0kV x100 100μm WD11mm



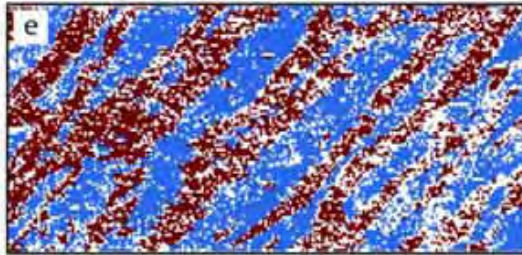
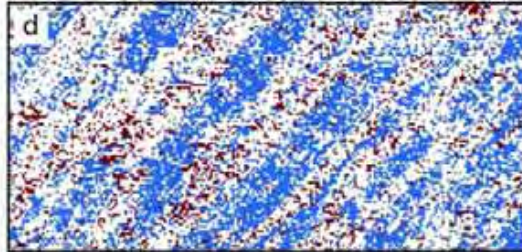
5  $\mu$ m

	(d) Step I	(e) Step III
	<i>low albite</i>	<i>refined albite</i>
	<i>match unit</i>	<i>match unit</i>
	<i>orthoclase</i>	<i>refined kfs</i>
	<i>match unit</i>	<i>match unit</i>





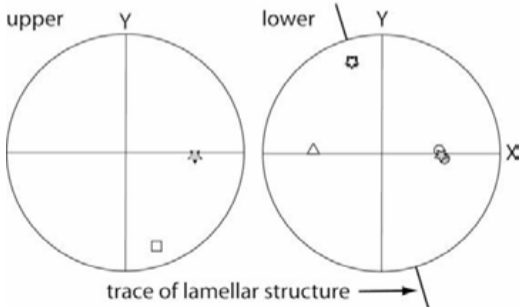
(d) Step I	(e) Step III
bytownite match unit	refined albite match unit
microcline match unit	refined kfs match unit

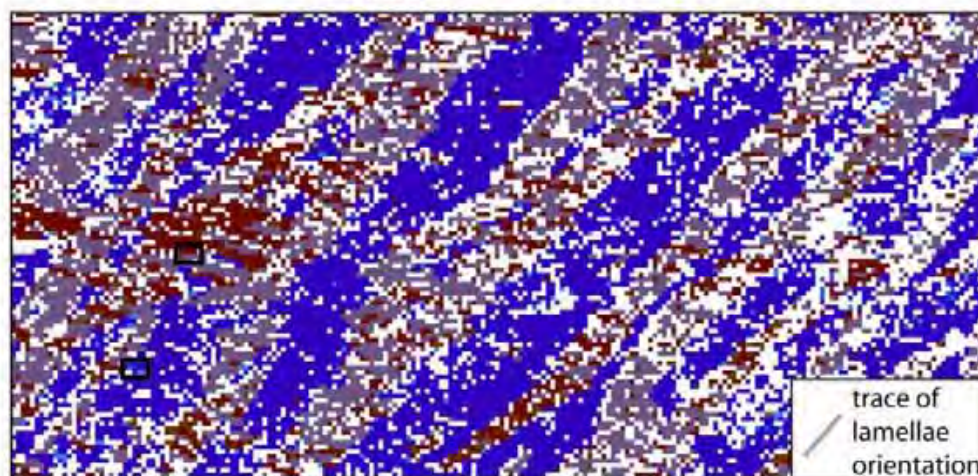
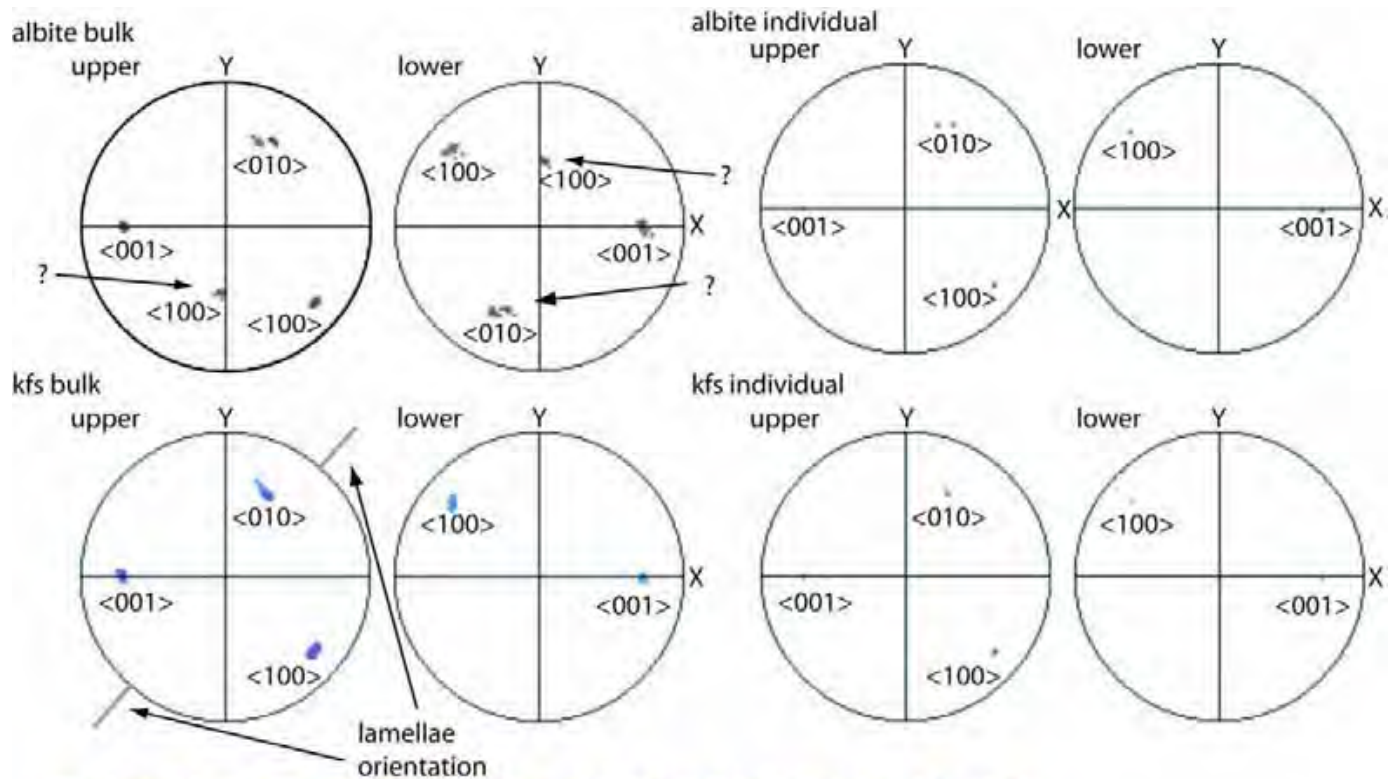


scale bar = 100  $\mu\text{m}$



	axes			
	$\langle 001 \rangle$	$\langle 010 \rangle$	$\langle 100 \rangle$	
albite	□	○	△	component 1
	▣	●	▲	component 2
kfs	☆	☆	✱	





- red brown albite twin
- dark blue light blue kfs twin
- location of individual twin pair data

